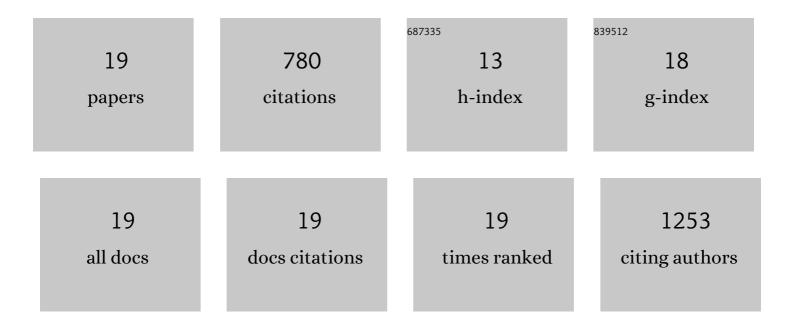
Aleksander Labuda

List of Publications by Year in descending order

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#	Article	IF	CITATIONS
1	Tapping Mode AFM Imaging in Liquids with blueDrive Photothermal Excitation. Microscopy Today, 2018, 26, 12-17.	0.3	13
2	Static and dynamic calibration of torsional spring constants of cantilevers. Review of Scientific Instruments, 2018, 89, 093701.	1.3	4
3	Fast, High Resolution, and Wide Modulus Range Nanomechanical Mapping with Bimodal Tapping Mode. ACS Nano, 2017, 11, 10097-10105.	14.6	110
4	Generalized Hertz model for bimodal nanomechanical mapping. Beilstein Journal of Nanotechnology, 2016, 7, 970-982.	2.8	65
5	Calibration of higher eigenmodes of cantilevers. Review of Scientific Instruments, 2016, 87, 073705.	1.3	40
6	Daniell method for power spectral density estimation in atomic force microscopy. Review of Scientific Instruments, 2016, 87, 033704.	1.3	5
7	Quantitative measurements of electromechanical response with a combined optical beam and interferometric atomic force microscope. Applied Physics Letters, 2015, 106, .	3.3	96
8	Contact resonance atomic force microscopy imaging in air and water using photothermal excitation. Review of Scientific Instruments, 2015, 86, 083706.	1.3	29
9	Bias-Dependent Molecular-Level Structure of Electrical Double Layer in Ionic Liquid on Graphite. Nano Letters, 2013, 13, 5954-5960.	9.1	142
10	Stochastic simulation of tip-sample interactions in atomic force microscopy. Applied Physics Letters, 2012, 101, 113105.	3.3	7
11	Retrofitting an atomic force microscope with photothermal excitation for a clean cantilever response in low Q environments. Review of Scientific Instruments, 2012, 83, 053703.	1.3	39
12	Atomic Force Microscopy in Viscous Ionic Liquids. Langmuir, 2012, 28, 5319-5322.	3.5	45
13	The noise of coated cantilevers. Nanotechnology, 2012, 23, 025503.	2.6	27
14	Stochastic noise in atomic force microscopy. Physical Review E, 2012, 86, 031104.	2.1	18
15	Exploiting cantilever curvature for noise reduction in atomic force microscopy. Review of Scientific Instruments, 2011, 82, 013704.	1.3	12
16	Switching Atomic Friction by Electrochemical Oxidation. Langmuir, 2011, 27, 2561-2566.	3.5	45
17	Decoupling conservative and dissipative forces in frequency modulation atomic force microscopy. Physical Review B, 2011, 84, .	3.2	46
18	High-resolution friction force microscopy under electrochemical control. Review of Scientific Instruments, 2010, 81, 083701.	1.3	36

#	Article	IF	CITATIONS
19	Robust and Efficient Parametric Spectral Density Estimation for High-Throughput Data. Technometrics, 0, , 1-22.	1.9	1